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- Motivation for thin films in SRF cavities
- History of thin film development
- Energetic Condensation
- Morphology of thin films produced by energetic condensation
- Thin films on Cu
- Future Plans





Motivation

- More than 10000 particle accelerators worldwide; most use normal cavities
- ScuSe normal scuse normal scuse normal large facilities can be built at ≈ half the employing a super less power than a advances, a employing a super less power ginally planned scrubble of that are advances and be be scrubble of that uner redu uner redu uner redu uner redu uner redu us sa sthe uner sa sa the uner redu us sa sthe uner sa sa the uner sa the uner sa sa the uner sa the uner

AASC's thin film superconductor development is aimed at these goals



LEP at CERN tested Cu cavities Magnetron sputter coated with ~1.5µm Nb thin films (1984-)

 C. Benvenuti, N. Circelli, M. Hauer, Appl. Phys. Lett. 45, 1984. 583; C. Benvenuti, Part. Accel. 40 1992. 43; C. Benvenuti, S. Calatroni, G. Orlandi in: 20th International conference on Low Temperature Physics, Eugene 1993, to be published in Physica B; C. Benvenuti, S. Calatroni, I.E. Campisi, P. Darriulat, M.A. Peck, R. Russo, A.-M. Valente, Physica C316, 1999, 153–188, (Elsevier): *Study of the surface resistance of superconducting niobium films at 1.5 GHz*

> RRR=11.5 on oxide coated Cu, 29 on oxide-free Cu coated at 150° C

- G.Amolds, Doktorarbeit, University of Wuppertal, WUB 79-14 (1979)
 - > Wuppertal studied 8, 3 and 1GHz Nb cells vapor deposition coated with Nb₃Sn



 \mathcal{C} Limitations of Magnetron sputtering and Vapor Deposition



dapnia

Advantages to use Thin Film Technology for SRF Cavities : Reduced Cost - New Superconducting Material (higher T_c & H_{sh})

saclay

severe Q-drop limits High Gradient Performances E_{acc} < 25 MV/m



(no field emission, no quench only RF power limitation)

Bernard Visentin

International Workshop on Thin Films - Legnaro - October 2006

24







10 cm

- R. Russo, A. Cianchi, Y.H. Akhmadeev, L. Catani, J. Langner, J. Lorkiewicz, R. Polini, B. Ruggiero, M.J. Sadowski, S. Tazzari, N.N. Koval, Surface & Coatings Technology 201 (2006) 3987–3992
 - Base pressure of 1–2×10⁻¹⁰ mbar in the system is reached after one night bake at 150 °C, but pressure increased to 10⁻⁷ mbar during run
 - > Laser trigger to minimize impurities in Nb film
 - > Magnetic sector filter to reduce macro-particles in film
 - Lattice parameter (from XRD spectra) showed much lower stress than observed in niobium deposited by magnetron sputtering
 - Surface roughness was ~few nm on sapphire and on Cu, was comparable to that of the Cu substrate itself
 - RRR of 20-50 was measured on ~1µm Nb films deposited on Quartz at room temperature (higher than typical sputtering values)

RRR up to 80 was reported with substrate heated to 200°C

- Dominant impurity was H atoms outgassed from Nb cathode (needed careful bakeout of cathode to minimize this problem
- J. Langner, R. Mirowski, M.J. Sadowski, P. Strzyzewski, J. Witkowski, S. Tazzari, L. Catani, A. Cianchi, J. Lorkiewicz, R. Russo, Vacuum 80 (2006) 1288–1293





- Motivation for thin films in SRF cavities
- History of thin film development for SRF cavities

Energetic Condensation (a very brief primer)

- Morphology of thin films produced by energetic condensation
- Thin films on Cu

Future Plans





Energetic Condensation



J.A. Thornton, "Influence of substrate temperature and deposition rate on the structure of thick sputtered Cu coatings", J. Vac. Sci. Technol. Vol. 12, 4 Jul/Aug 1975

Andre Anders, A structure zone diagram including plasma-based deposition and ion etching, Thin Solid Films 518 (2010) 4087–4090

- In Energetic Condensation, the ions deposit energy in a sub-surface layer (≈3 atomic layers deep for ~100eV Nb ions), shaking up the lattice, causing adatom mobility and promoting epitaxial crystal growth
- Energetic Condensation when combined with substrate heating promotes lower-defect crystal growth





- Y. Lifshitz, S. R. Kasi, J.Rabalais, W. Eckstein, Phy. Rev. B Vol. 41, #15, 15 May 1990-II: Subplantation model for film growth from hyperthermal species
- D.K. Brice, J.Y. Tsao and S.T. Picraux: PARTITIONING OF ION-INDUCED SURFACE AND BULK DISPLACEMENTS
- W. D. Wilson, Radiat. Eff. 78, 11 (1983)





Thermal-Vacuum Stability of the Surface Oxide Complex on Cu

M. Bagge-Hansen, R.A. Outlaw, K. Seo, C. Reese, J. Spradlin, Anne Marie Valente-Feliciano and D.M. Manos, Journal of Vacuum Science and Technology (2011), in press



Challenges for thin film SRF: path to success

Cu and/or AI cavity substrates might be of two different forms



- How do we grow low-defect Nb films on such substrates?
- Study adhesion, thickness, smoothness, RRR, stability
- Understand these issues at the coupon level
- Proceed to RF cavity level and measure Q at high fields
- Install multi-cell Nb coated Cu modules in SRF accelerator and validate the thin film solution
 - ◊ Spur acceptance of thin film Nb by accelerator community
- \blacklozenge Continue R&D towards higher T_c films and AI cavities





Coaxial Energetic Deposition (CED) Coater at AASC



Coaxial Energetic Deposition (CED[™])



- ◆ CED coater uses "welding torch" technology
- ♦ Arc source is scalable to high throughputs for large scale cavity coatings
 - > Present version deposits ≈1 monolayer/pulse in ≈1ms
- ◆ Russo's and Langner's emphasis on UHV and clean walls is important



CAD: Pulsed Biased deposition; Dual Targets



Cathodic Arc Deposition (CAD)



Pulsed Bias capability



* A. BENDAVID, P. J. MARTIN, R. P. NETTERFIELD, G. J. SLOGGETT, T. J. KINDER, C., ANDRIKIDIS, JOURNAL OF MATERIALS SCIENCE LETTERS 12 (1993) 322-323



vol under gaussian=	0.012	CC
mass under gaussian=	0.100	g
mass/shot=	14.3	μg
charge/shot=	0.5	С
anode transm.=	0.7	
erosion rate=	41	µg/C
peak thickness/pulse=	5.6	Å
instant. rate=	5600	Å/s



Dual Target source for Nb₃Sn, Mo₃Re, MgB₂ etc.

Please visit Poster THPO077 on Thursday: Mo-Re Films for SRF Applications", Dr. Enrique Valderrama





- AASC's UHV Arc coater (CED/CAD) and JLab's ECR source are both Energetic Condensation Coaters
 - ◇ The CED/CAD plasma generates Nb²⁺ and Nb³⁺ ions with 40-120eV energy spread
 - $_{\odot}\,$ The ECR plasma also produces ~100eV ions by biasing the substrate, with Nb^+ ions

 AASC and JLab collaborate on thin film development for SRF. Over the past year, we have achieved record RRR values in Nb films

- $\diamond~$ RRR=585 in Nb on MgO using CED
- ◊ RRR=488 in Nb on a-sapphire using ECR
- ◊ RRR=289 in Nb on LG Cu using ECR

Please see A-M Valente Feliciano' s talk later in this session!

 We are learning more about the epitaxial growth modes on different substrates, building a knowledge base from which to proceed to Cu cavity coatings in the near future





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RRR of Nb thin films on sapphire and MgO substrates

 Nb thin films grown on sapphire and MgO crystals have demonstrated higher levels of RRR than were reported by the pioneers, and XRD spectra reveal crucial features



 M. Krishnan, E. Valderrama, B. Bures, K. Wilson-Elliott, X. Zhao, L. Phillips, Anne-Marie Valente-Feliciano, Joshua Spradlin, C. Reece, K. Seo, submitted to Superconducting Science and Technology







G. Orlandi, C. Benvenuti, S. Calatroni, F. Scalambrin, *Expected dependence of Nb-coated RF cavity* performance on the characteristics of niobium, Proc. Of 6th workshop on RF Superconductivity, CEBAF, (1993)



Ad hoc model fit to <RRR> data

RRR of Nb thin films on a-sapphire substrates

• XRD Pole Figures show that higher RRR correlates with higher crystalline order



"Twin symmetry texture of energetically condensed niobium thin films on sapphire substrate (a-plane Al2O3)", X. Zhao, L. Philips, C. E. Reece, Kang Seo, M. Krishnan, E. Valderrama, Journal of Applied Physics, Vol 115, Issue 2, 2011, [in-press],





RRR of Nb thin films on MgO substrates

• Pole Figures show change in crystal orientation from 110 to 200 at higher temperature



• Please visit poster THP0042 (given by Xin Zhao of JLab) for more details



Nb on MgO: temp. driven transition in crystal orientation

- EBSD data shows intermixed Nb (110) and Nb (100) for lower RRR samples
- High RRR samples show pure Nb (100) for the entire surface

RRR = 196, 500/500



EBSD shows 110 to 100 transition (Pole figure captures the 200 plane):



RRR = 333, 600/500

Observations about bulk single crystal Nb orientation

PERFORMANCE OF SINGLE CRYSTAL NIOBIUM CAVITIES, **P. Kneisel**, G. Ciovati, TJNAF, Newport News, VA 23606, U.S.A. W. Singer, X. Singer, D. Reschke, A. Brinkmann, Proceedings of EPAC08, Genoa, Italy MOPP136

PROGRESS ON LARGE GRAIN AND SINGLE GRAIN NIOBIUM – INGOTS AND SHEET AND REVIEW OF PROGRESS ON LARGE GRAIN AND SINGLE GRAIN NIOBIUM CAVITIES, **P. Kneisel**, Proceedings of SRF2007, Peking Univ., Beijing, China



Figure 4: Q_0 vs. E_{acc} at 2 K for single crystal cavities #4 and #5 (best performance).

Cavity #5 showed a different behavior than all other single crystal/large grain cavities after baking: the Q-drop did not disappear after 12 hours. The crystal orientation of the single crystals of this cavity was (110) with a tilt against the surface. For cavity #4 the crystal orientation was (100).

The surface of both cavities appeared quite different after BCP: whereas cavity #4 exhibited a very smooth, shiny surface, the surface of cavity #5 was "rough" (orange peel/fish scale appearance) and less shiny.

Obviously, there is a difference in the reaction of the BCP chemicals at different crystal orientations {D. Baars et al., "Crystal orientation effects during fabrication of single or multi-crystal Nb SRF cavities", SRF07, Beijing, Oct. 2007, TH102; http://www.pku.edu.cn/academic/srf2007/proceeding}

Could CED (Energetic Condensation) be used to grow (100) Nb films on existing Nb cavities to help improve performance?





RRR-7: Cross sectional EBSD (OIM)

BSE image – Cross sectional view



Nb thin film layer

MgO layer -MgO IPF map

001

celerator Facility

Jefferson Lab

111

101



Lower CI values between Nb matrix and MgO substrate indicate that there could be an amorphous or non-structured layer between them





RRR-196: Cross sectional EBSD: shows mix of (110) and (100)











RRR-316: Cross sectional EBSD







TEM/AFM of high RRR samples



- Energetic Condensation (subplantation) physics drives an adhesive, nonporous, dense interface between substrate and Nb film
- ◆Nb surface is smooth (~5nm roughness)



"Mold" effect of subplanted Nb films: low RRR film



The macroparticle acquires the same crystallite structure as does the underlying Nb thin film that preceded it . This is for a low RRR film.



"Mold" effect of subplanted Nb films: high RRR film





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aasc10vp01-26



- Macro-particles appear to have the same crystal structure as subplantation grown films
- Macroparticles arrive at surface with very low kinetic energy but T/T_m ~1



Can we develop a "hybrid" growth concept in which Energetic Condensation plants the seed and then pure molten metal is poured on this seed, to develop a highly crystalline order via the "mold" effect?





SIMS with Cs beam of high RRR Nb films:



H count rate (normalized) in thin films is 7x10³ times lower than in bulk Nb!



 Nb thin films grown on amorphous borosilicate show a similar trend of higher RRR with higher substrate temperature



One option for Nb-on-Cu growth is to first "amorphize" the substrate by high energy "subplantation", then attempt to drive Nb crystal growth Aluminum substrates would also use this approach. *Borosilicate is a proxy*

Please visit THPO069 on Thursday: Nb Film Growth on Crystalline and Amorphous Substrates" Dr. Enrique Valderrama



XRD Pole Figures for Nb thin films grown on Borosilicate

Subplantation physics of energetic condensation at work here

(110) Nb on Borosilicate at 150/150C



A strong [110] Nb fiber structure perpendicular to the substrate

At higher coating temperature, in-plane texture shows that [110] fiber texture is highly oriented to the substrate

[110]

(110) Nb on Borosilicate at 400/400C



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~50µm grains of Nb measured in 0.4µm thick films on Cu

"Large crystal grain niobium thin films deposited by energetic condensation in vacuum arc", X. Zhao, A.-M. Valente-Feliciano, C. Xu, R. L. P. Geng, L., C. E. Reece, K. Seo, R. Crooks, M. Krishnan, A. Gerhan, B. Bures, K. W. Elliott, and J. Wright, Journal of Vacuum Science & Technology A 27, 620-625 (2009).



$\stackrel{\sim}{\sim}$ CEDTM Nb Film on polycrystalline Cu substrate: Hetero-epitaxy



Energetic Condensation demonstrated growth of very large Nb grains on Cu. Please see Anne-Marie's talk later for recent RRR and other data from an ECR source





Vielen Dank

Fragen, bitte?







Thicker films must be analyzed before we can do a better model fit





SIC measurements at JLab

R_s vs. T: thin film Nb on Cu sample TF-AASC-CED-103; EP, annealed at 750 C, then EP again





RRR of Nb thin films on c-sapphire substrates

◆ Pole Figures show better crystal structure at higher temperature





RRR of Nb thin films on c-sapphire substrates

Pole Figures show better crystal structure at higher temperature



 Despite high crystalline order, RRR is only 43. High order is a necessary condition for high RRR, but film might have impurities that limit electron mean free path.





				# of		anneal			base
sample ID	RRR	error bar	T_c	shots	delta, µm	temp	dep temp	substrate	pressure
CED-113010-66	541	10%	9.30	20000	3.67	700	500	MgO(100), MTI, 2 x1 cm^2	2.60E-08
CED-120310-68	554	25%	9.30	30000	5.50	700	500	MgO(100), MTI, 1 x1 cm^2	2.70E-08
CED-120310-69	585	1%	9.34	30000	5.5	700	500	MgO(100), MTI, 1 x1 cm^2	2.70E-08

